TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74HC697AP,TC74HC697AF

Synchronous Presettable 4-Bit Binary Up/Down Counter with Output Register (multiplexed 3-state outputs)

The TC74HC697A is high speed CMOS UP/DOWN COUNTERS fabricated with silicon gate C²MOS technology. It achieve the high speed operation similar to equivalent

LSTTL while maintaining the CMOS low power dissipation.

It counts on the rising edge of the Counter Clock (CCK) input when "counter mode" is selected. If the up/down (U/\overline{D}) input is held high, the internal counter counts up. Conversely, if U/\overline{D} is held low, it counts down.

The internal counters outputs are latched into the output registers on the rising edge of the Register Clock (RCK) input.

The outputs (QA~QD) are selected as either internal counter or registered outputs by the output select (R/\overline{C}) input. When high, the outputs are counter outputs and when low, they are registered outputs.

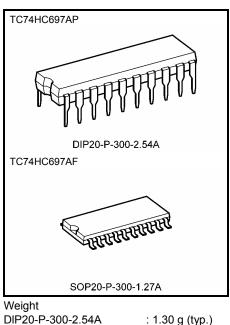
Two enable $(\overline{\text{ENP}}, \overline{\text{ENT}})$ inputs and a carry $(\overline{\text{RCO}})$ output are provided to enable cascading of the counters.

This facilitates easy implementation of n-bit counters without using external gates.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

Features

- High speed: $f_{max} = 38$ MHz (typ.) at V_{CC} = 5 V
- Low power dissipation: $I_{CC} = 4 \mu A \pmod{at Ta} = 25 \circ C$
- High noise immunity: $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (min)
- Outputs drive capability: 15 LSTTL loads for QA~QD 10 LSTTL loads for RCO
- Symmetrical output impedance:
 - $|IOH| = IOL = 6 \text{ mA} (min) \text{ for } QA \sim QD$
 - $|I_{OH}| = I_{OL} = 4 \text{ mA (min) for } \overline{RCO}$
- Balanced propagation delays: $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range: V_{CC} (opr) = 2~6 V
- Pin and function compatible with 74LS697

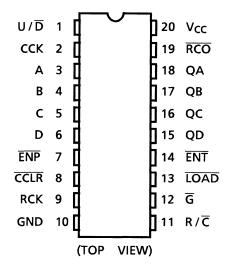


DIP20-P-300-2.54A SOP20-P-300-1.27A : 0.22 g (typ.)

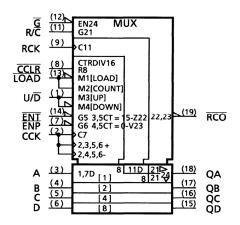
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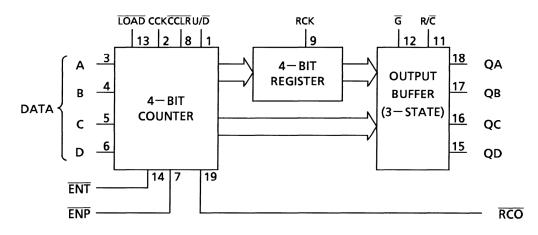
Pin Assignment



IEC Logic symbol



Block Diagram



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Truth Table

			Inp	outs						Out	puts		Function	
CCLR	LOAD	ENP	ENT	ССК	U/D	RCK	R/C	G	QA	QB	QC	QD	Function	
х	х	х	Х	Х	Х	Х	Х	Н	Z	Z	Z	Z	Z	
L	Х	Х	Х	Х	Х	Х	L	L	L	L	L	L	Clear Counter	
н	L	х	х		Х	х	L	L	a b c d			Load Counter		
Н	Н	Н	Х		Х	Х	L	L	- No Change				No Count	
н	Н	х	Н		х	х	L	L						
Н	Н	L	L		Н	х	L	L		Cour	nt Up		Count	
н	Н	L	L		L	х	L	L		Count	Down		Count	
Н	Х	Х	Х		Х	Х	L	L	No Change				No Count	
х	Х	Х	Х	Х	Х		Н	L	a' b' c' d'		Load Register			
х	Х	Х	Х	Х	Х		Н	L	No Change				No Count	

X: Don't care

Z: High impedance

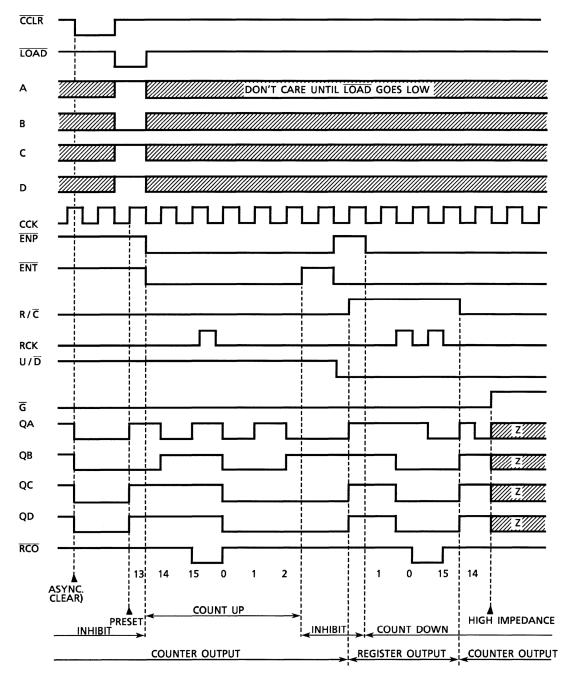
a~d: The level of steady state inputs at inputs A through D respectively.

a'~d': The level of steady state outputs at internal counter outputs QA' through QD' respectively.

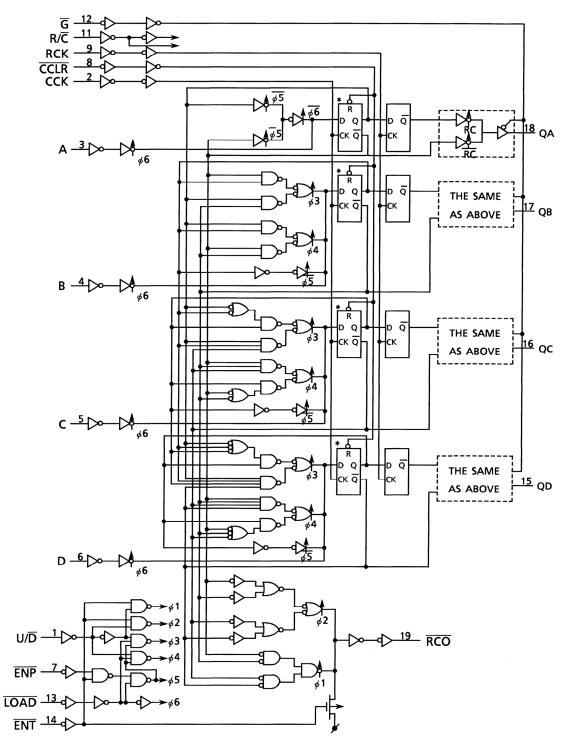
 $\overline{\mathsf{RCO}} = (\overline{\mathsf{UP}} \cdot \mathsf{QA} \cdot \mathsf{QB} \cdot \mathsf{QC} \cdot \mathsf{QD} \cdot \mathsf{ENT} + \overline{\mathsf{UP}} \cdot \overline{\mathsf{QA}} \cdot \overline{\mathsf{QB}} \cdot \overline{\mathsf{QC}} \cdot \overline{\mathsf{QD}} \cdot \mathsf{ENT})$

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Timing Chart



System Diagram



Absolute Maximum Ratings (Note 1)

Characteristic	CS	Symbol	Rating	Unit
Supply voltage range		V _{CC}	-0.5~7	V
DC input voltage		V _{IN}	$-0.5 \sim V_{CC} + 0.5$	V
DC output voltage		V _{OUT}	$-0.5 \sim V_{CC} + 0.5$	V
Input diode current		I _{IK}	±20	mA
Output diode current		IOK	±20	mA
DC output current	(RCO)	laum.	±25	mA
DC output current	(QA~QD)	Ιουτ	±35	ma
DC V _{CC} /ground current		ICC	±75	mA
Power dissipation		PD	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature		T _{stg}	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = -40 to 65° C. From Ta = 65 to 85° C a derating factor of -10 mW/°C shall be applied until 300 mW.

Characteristics	Symbol	Rating	Unit
Supply voltage	V _{CC}	2~6	V
Input voltage	VIN	0~V _{CC}	V
Output voltage	V _{OUT}	0~V _{CC}	V
Operating temperature	Topr	-40~85	°C
		0~1000 (V _{CC} = 2.0 V)	
Input rise and fall time	t _r , t _f	$0 \sim 500 \ (V_{CC} = 4.5 \ V)$	ns
		0~400 (V _{CC} = 6.0 V)	

Operating Ranges (Note)

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

Electrical Characteristics

DC Characteristics

		Test Condition				-	Га = 25°С)	Ta = -4		
Characteristics	Symbol				V _{CC} (V)	Min	Тур.	Max	Min	Max	Unit
					2.0	1.50	_	_	1.50	—	
	VIH				4.5	3.15	—	_	3.15	—	V
· · · · · · · · · · · · · · · · · · ·					6.0	4.20	—	_	4.20	Max Max </td <td></td>	
					2.0	_		0.50		0.50	
High-level input voltage	V _{IL}				4.5	_	—	1.35		1.35	V
						_	—	1.80		1.80	
					2.0	1.9	2.0	_	1.9	_	
		V _{IN} = Vін	or V _{IL}	$I_{OH} = -20 \ \mu A$	4.5	4.4	4.5	—	4.4	—	
	V _{OH}	- 111			6.0	5.9	6.0	—	5.9	—	
			RCO	$I_{OH} = -4 \text{ mA}$	4.5	4.18	4.31	_	4.13	_	V
			RCO	$I_{OH} = -5.2 \text{ mA}$	6.0	5.68	5.80	—	5.63	—	
				I _{OH} = -6 mA	4.5	4.18	4.31	_	4.13	_	
			QA~QD	$I_{OH} = -7.8 \text{ mA}$	6.0	5.68	5.80	—	5.63	—	
					2.0	_	0.0	0.1		0.1	
		$V_{IN} = V_{IH}$	or Vu	$I_{OL}=20~\mu A$	4.5	_	0.0	0.1		0.1	
		- 111			6.0	_	0.0	0.1		0.1	
	V _{OL}		RCO	$I_{OL} = 4 \text{ mA}$	4.5	_	0.17	0.26		0.33	V
			RCO	$I_{OL} = 5.2 \text{ mA}$	6.0	_	0.18	0.26		0.33	
			QA~QD	$I_{OL} = 6 \text{ mA}$	4.5	_	0.17	0.26		0.33	
			QA~QD	$I_{OL} = 7.8 \text{ mA}$	6.0	_	0.18	0.26	_	0.33	
3-state output off-state current	I _{OZ}		$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or } GND$					±0.5	_	±5.0	μΑ
Input leakage current	I _{IN}	V _{IN} =	V _{CC} or G	ND	6.0			±0.1		±1.0	μA
Quiescent supply current	ICC	V _{IN} =	V _{CC} or G	ND	6.0			4.0		40.0	μA

Timing Requirements (input: $t_r = t_f = 6 \text{ ns}$)

Characteristics	Symbol Test Condition			Ta = 25°C		Ta = _40 ~85°C	Unit
	Symbol tw (L) tw (H) tw (H) ts		V _{CC} (V)	Тур.	Limit	Limit	
Minimum pulse width	*		2.0	_	75	95	
(CCK, RCK)		—	4.5	—	15	19	ns
	۷۷ (H)		6.0	_	13	16	
Minimum pulse width			2.0		75	95	
(CCLR)	t _{W (L)}	—	4.5	—	15	19	ns
(COLK)			6.0	_	13	16	
Minimum set-up time			2.0		150	190	
$(\overline{\text{LOAD}}, \overline{\text{ENT}}, \overline{\text{ENP}})$	ts	—	4.5	—	30	38	ns
(LOAD, ENT, ENF)			6.0	_	13	32	
Minimum set-up time			2.0		50	65	
(A, B, C, D)	ts	—	4.5	—	10	13	ns
(Ҳ, Ҍ, ҄Ѻ, Ѣ)			6.0	_	9	~85°C Limit 95 19 16 95 19 16 95 19 16 190 38 32 65 13 125 21 5 5 0 0 0 5 5 5 5 4 20	
Minimum set-up time			2.0		100	125	
(U/\overline{D})	ts	—	4.5	—	20	25	ns
(0,0)			6.0	_	17	65 13 11 125 25 21 125 25 21 25 21 5	
Minimum set-up time			2.0		100	125	
(CCK-RCK)	ts	—	4.5	—	20	25	ns
			6.0	_	17	21	
Minimum hold time			2.0		5	5	
(A, B, C, D)	t _h	—	4.5	—	5	5	ns
(A, B, C, D)			6.0	_	5	5	
			2.0		0	0	
Minimum hold time	t _h	—	4.5	—	0	0	ns
			6.0	_	0	0	
			2.0	_	5	5	
Minimum removal time	t _{rem}	—	4.5	—	5	5	ns
			6.0	_	5	5	
			2.0	_	5	4	
Clock frequency	f	_	4.5	—	25	20	MHz
			6.0	—	29	24	

AC Characteristics (C_L = 15 pF, V_{CC} = 5 V, Ta = 25°C, input: $t_r = t_f = 6$ ns)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Output transition time $(\overline{\text{RCO}})$	tтLH tтHL	_	_	4	8	ns
Propagation delay time (CCK- RCO)	t _{pLH} t _{pHL}	_	_	24	41	ns
Propagation delay time (ENT- RCO)	t _{pLH} t _{pHL}	_	_	13	23	ns
Propagation delay time (CCLR - RCO)	^t pLH	_	_	23	38	ns
Maximum clock frequency	f _{max}	—	25	38	_	MHz

AC Characteristics (input: $t_r = t_f = 6 \text{ ns}$)

		Test Conditi	on		-	Ta = 25°0)	Ta = -4		
Characteristics	Symbol		CL (pF)	V _{CC} (V)	Min	Тур.	Max	Min	Max	Unit
Output transition time	t			2.0	_	25	60	_	75	
(Qn)	t _{TLH}	_	50	4.5	—	7	12	—	15	ns
	t _{THL}			6.0	—	6	10	—	13	
Output transition time	t _{pLH}			2.0	—	30	75	—	95	
(RCO)	ъсн t _{pHL}	_	50	4.5	—	8	15	—	19	ns
(чрн∟			6.0	_	7	13	—	16	
				2.0	—	90	195	—	245	
Dranagation dalay			50	4.5	—	26	39	—	49	
Propagation delay time	t _{pLH}	_		6.0	_	19	33	—	42	ns
(CCK-Q)	t _{pHL}			2.0	—	103	235	—	295	
			150	4.5	—	31	47	—	59	
				6.0	—	23	40	—	50	
				2.0	—	82	180	—	225	
Deve exetient delay			50	4.5	—	24	36	—	45	
Propagation delay time	t _{pLH}			6.0	—	18	31	—	38	ns
(RCK-Q)	t _{pHL}			2.0	—	95	220	—	275	
			150	4.5	—	29	44	—	55	
				6.0	—	22	37	—	47	
				2.0	—	60	145	—	180	
Deve exetient delay			50	4.5	—	19	29	—	36	
Propagation delay time	t _{pLH}			6.0	—	14	25	—	31	ns
(R/C -Q)	t _{pHL}			2.0	—	73	185	—	230	
			150	4.5	—	24	37	—	46	
				6.0	—	18	31	—	47 180 36 31 230 46	
				2.0	—	89	195	—	245	
Dranagation dalay			50	4.5	—	26	39	—	49	
Propagation delay time	t _{pHL}	_		6.0	—	20	33	—	42	ns
(CCLR -Q)	φnL			2.0	—	102	235	—	295	
			150	4.5	—	31	47	—	59	
				6.0	_	24	40		50	
Propagation delay	tpLH			2.0	—	108	235	—	295	
	t _{pHL}	—	50	4.5	—	31	47	-	59	ns
(CCK-RCO)	רוץי		ļ	6.0	_	23	40		50	
Propagation delay	t _{pLH}			2.0	—	63	135	—	170	
	ърсн tpHL	—	50	4.5	—	18	27	—	34	ns
(ENT - RCO)	דוץי			6.0	_	14	23		29	
Propagation delay				2.0	—	98	220	—	275	
time	t _{pLH}	—	50	4.5	—	29	44	—	55	ns
$(\overline{CCLR} - \overline{RCO})$				6.0		23	37	—	47	

<u>TOSHIBA</u>

	Test Conditio				-	Га = 25°С)	Ta = -4		
Characteristics	Symbol		CL (pF)	V _{CC} (V)	Min	Тур.	Max	Min	- 145 - 29 - 25 - 195 - 39 - 33 - 145 - 29 - 25 - 25 - 4 10	Unit
				2.0	_	45	115		145	
			50	4.5	_	15	23		29	
Output enable time	t _{pZL}	$R_{I} = 1 k\Omega$		6.0		12	20		25	ns
(G -Q)	t _{pZH}			2.0		58	155	_	195	115
			150	4.5	_	20	31		39	
				6.0	_	16	26		33	
Output disable time	t . –			2.0	_	32	115	_	145	
·	t _{pLZ}	$R_L = 1 \ k\Omega$	50	4.5	_	17	23		29	ns
Output disable time $(\overline{G} - Q)$	^t pHZ			6.0	_	14	20		25	
				2.0	5	11	_	4	_	
Maximum clock frequency	f _{max}	—	50	4.5	25	38	—	20	_	MHz
- 1				6.0	29	52	_	24	—	
Input capacitance	CIN	—			_	5	10	_	10	pF
Output capacitance	COUT	_			_	13	_			pF
Power dissipation capacitance	C _{PD} (Note)	_			_	72			_	pF

Note: CPD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

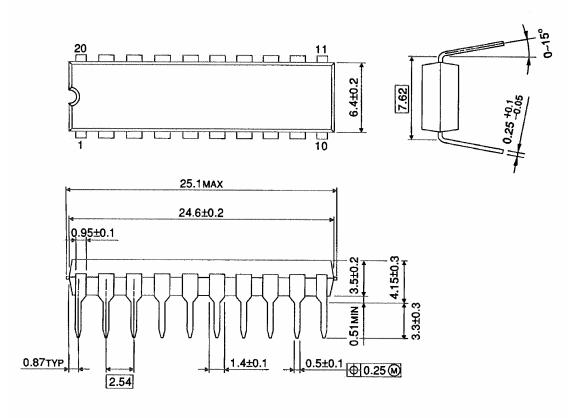
Average operating current can be obtained by the equation:

 I_{CC} (opr) = $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$

Package Dimensions

DIP20-P-300-2.54A

Unit : mm

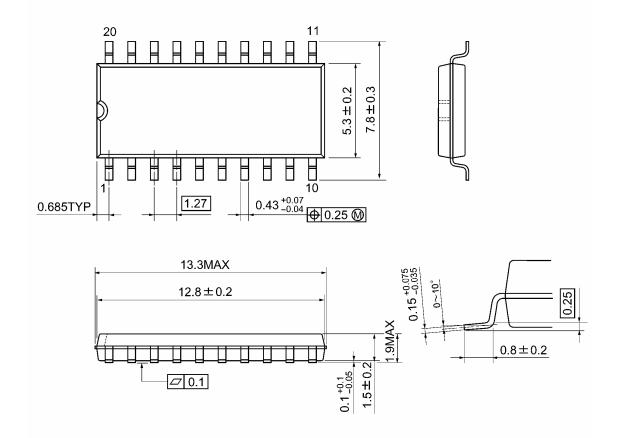


Weight: 1.30 g (typ.)

Package Dimensions

SOP20-P-300-1.27A

Unit: mm



Weight: 0.22 g (typ.)

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20070701-EN GENERAL

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